Design Automation

The Minutes of the DA-WG
on the 14th JISC-CENELEC
Information Exchange meeting

IEC TC93 (Design Automation)

SCOPE:

to enable the integration and automation of electrotechnical product design, engineering, manufacturing, and logistics support processes, and to facilitate procedures for product operation and maintenance.

IEC TC93 Organization

Chairman	Osamu Karatsu (Japan)
Secretary	Victor Berman (USA)

WG1: Electronical data harmonization
WG2: Component, circuit and system description languages
WG3: Reference model for electronic design interchange format
WG5: Test, validation, conformance and qualification technologies
WG6: Library of Reusable Parts for Electrotechnical Products
WG7: Testing of Electrotechnical Products
JWG11: Product description standard for printed board, printed board assembly, and testing in XML schema
(Joint working with TC91)

Attendees of JISC-CENELEC design automation meeting

Dr. W. Wikes	Germany
Dr. R. Nerke	Germany
Mr. F. Andreolli	Italy
Mr. M. Graham	United Kingdom
Mr. M. Teigeler	Germany
Dr. O. Karatsu	Japan
Dr. T. Kambe	Japan
Mr. M. Takahashi	Japan

1. Current status of each organization

- JISC
  - IEC/TC93 and JNC activities by Kambe
  - Common rule for exchange methodology of product technological attribute information by Mr. Takahashi
- CENELEC
  - Library standards and existing dictionaries by Dr. Nerke
  - Catalogue Exchange and Business Processes in connection with ISO 29002 by Dr. Wilkes
- Q&A

2. standards of electronic catalogue data exchange

- Draft proposal of TC93/WG6 by Mr. Takahashi
- Discussions
  - The relationship with other standards
  - Mapping methodology

Next step of this meeting

- Create landscape to visualize how the effort fits into the overall catalogue data exchange efforts.
- Thus it eventually creates synergies and already existing work can be easily identified.
- Such an overview will help to
  - Attract additional resources;
  - Help to find synergies;
  - Clearly shows where already existing standards are referenced;
  - Identify already existing work and thus avoid duplicated efforts.

Next meeting candidates

- ISO TC184/SC4 meeting at UK on May 23-28, 2010.
- IEC/ SC3D WG2 meeting in Japan on June or July, 2010
- Next CENELEC/JISC meeting in Japan, 2010
- ISO TC184/SC4 meeting at Italy on October 10-15, 2010.
- IEC general meeting (TC93) at Seattle in October, 2010.

We will decide the time and place by E-mail communication.